

Session Title:	[We1E] Dimensional Metrology IV
Session Date:	August 7 (Wed.), 2024
Session Time:	09:00-10:30
Session Room:	Room E (114)
Session Chair(s)	Prof. Heejoo Choi (Univ. of Arizona, USA), Dr. Heulbi Ahn (Meterlab, Korea)

[We1E-1] [Invited] 09:00-09:30

Calibration of a Reflective-type Diffraction Scale Grating Based on the Angle of Diffraction of Diffracted Beams for Precision Positioning Technology

Yuki Shimizu (Hokkaido Univ., Japan)

[We1E-2] 09:30-09:45

One-shot Three-dimensional Measurement Based on Spectral Interferometry using a Digital Micromirror Device

Jinxu Zhang, Liheng Shi (Tsinghua Univ., China), Yingying Gu, Donglai Zhang, Lu Yin (Beijing Inst. of Control Engineering, China Academy of Space Tech., China), and Guan hao Wu (Tsinghua Univ., China)

[We1E-3] 09:45-10:00

Improvement of Measurement Precision in Comb-mode Resolved Spectral Interferometry via Programmable Line-by-line Spectral Shaping of Frequency Comb

Yoon-Soo Jang, Sunghoon Eom, Jungjae Park, and Jonghan Jin (KRISS, Korea)

[We1E-4] 10:00-10:15

Frequency-comb-referenced Multi-wavelength Interferometry for High-speed 3D Reconstruction of μ -bumps in Heterogeneous Integration Packaging

Jun Hyung Park, Dae Hee Kim, Jiwon Hahm, Young Ho Park, Huy Hoang Chu, Seung-Woo Kim, and Young-Jin Kim (KAIST, Korea)

[We1E-5] 10:15-10:30

Distance Error Correction for Time-of-Flight Cameras with Interchangeable Lenses

Ting-Hsu Huang, Chi-Jin Liu, and Yi-Chun Chen (Nat'l Yang Ming Chiao Tung Univ., Taiwan)